Se	arch No	tes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/818,285	BENCO ET AL.

EMEM EKONG

Examiner

Reexamination
BENCO ET AL.
Art Unit
2688

	SEAR	CHED	
Class	Subclass	Date	Examiner
455	414.1 414.2 415 418 419 433 405 408	11/2/2005	EOE
	406 453		
455	452.2	:	
379	157-158		
370	259-271		
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(INCLUDING S	CH NOTES EARCH STRATEG	Y)
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